

INCH-POUND

MIL-PRF-55365D
AMENDMENT 1
13 April 1998

PERFORMANCE SPECIFICATION

CAPACITOR, FIXED, ELECTROLYTIC (TANTALUM), CHIP, NONESTABLISHED RELIABILITY,
ESTABLISHED RELIABILITY, GENERAL SPECIFICATION FOR

This amendment forms a part of MIL-PRF-55365D, dated 3 July 1997, and is approved for use by all Departments and Agencies of the Department of Defense.

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4.7.14e, delete and substitute:

“e. Measurements during the exposure: DC leakage at the applicable high test temperature shall be measured as specified in 4.7.4 at 0 hour; 240 hours +72, -24 hours; 1,000 hours, +72, -24 hours; and 2,000 hours, +96, -0 hours.”

4.7.14.1, delete and substitute:

“4.7.14.1 Extended life (exponential only). Capacitors shall be tested as specified in 4.7.14, except that the test temperature shall be +85°C, +4°C, -0°C, and the duration of the test shall be 10,000 hours. DC leakage shall be measured as specified in 4.7.4 at +85°C, +4°C, -0°C at 0 hour; 240 hours, +72, -24 hours; 1,000 hours, +72, -24 hours; 2,000 hours, +96, -24 hours; and every 2,000 hours, +96, -24 hours thereafter until 10,000 hours, +120, -0 hour have elapsed. Final measurements shall be as specified in 4.7.14f.”

Custodians:
Army - CR
Navy - EC
Air Force - 85

Review activities:
Army - AR, MI
Navy - AS, CG, MC, OS, SH
Air Force - 17, 19, 99
DLA - CC

Preparing activity:
Army - CR

Agent:
DLA - CC

(Project 5910-1965)